

AO3413 20V P-Channel MOSFET

General Description

The AO3413 uses advanced trench technology to provide excellent R_{DS(ON)}, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications.

Features

 $V_{DS} = -20V$

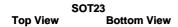
 $I_D = -3A$

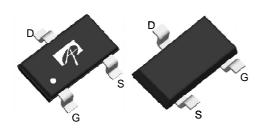
 $R_{DS(ON)} < 80 m\Omega$

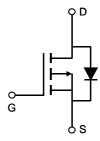
 $(V_{GS} = -4.5V)$ $(V_{GS} = -4.5V)$ $(V_{GS} = -2.5V)$ $(V_{GS} = -1.8V)$ $R_{DS(ON)} < 100 m\Omega$

 $R_{DS(ON)} < 130 m\Omega$









Absolute Maximum Ratings T_A=25℃ unless otherwise noted

Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		V_{DS}	-20	V	
Gate-Source Voltage		V_{GS}	±8	V	
Continuous Drain	T _A =25℃		-3		
Current ^A	T _A =70℃	'D	-2.4	Α	
Pulsed Drain Current B		I _{DM}	-15	7	
	T _A =25℃	Ь	1.4	W	
Power Dissipation ^A	T _A =70℃	P _D	0.9	VV	
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 150	C	

Thermal Characteristics								
Parameter		Symbol Typ Ma		Max	v Units			
Maximum Junction-to-Ambient A	t ≤ 10s	D	70	90	℃/W			
Maximum Junction-to-Ambient A	Steady-State	$R_{ hetaJA}$	100	125	℃/W			
Maximum Junction-to-Lead ^C	Steady-State	$R_{ heta JL}$	63	80	℃/W			



Electrical Characteristics (T_J=25℃ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-20V, V _{GS} =0V			-1	
		T _J =55℃			-5	μΑ
I_{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} =±8V			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ $I_{D}=-250\mu A$	-0.4	-0.65	-1	V
$I_{D(ON)}$	On state drain current	V_{GS} =-4.5V, V_{DS} =-5V	-15			Α
R _{DS(ON)}	Static Drain-Source On-Resistance	V_{GS} =-4.5V, I_D =-3A		56	80	mΩ
		T _J =125℃		80	115	
		V_{GS} =-2.5V, I_{D} =-2.6A		70	100	mΩ
		V_{GS} =-1.8V, I_D =-1A		85	130	mΩ
g _{FS}	Forward Transconductance	V_{DS} =-5V, I_{D} =-3A		12		S
V_{SD}	Diode Forward Voltage	$I_S=-1A, V_{GS}=0V$		-0.7	-1	V
Is	Maximum Body-Diode Continuous Current				-1.4	Α
DYNAMIC	PARAMETERS					
C _{iss}	Input Capacitance			560	745	pF
C _{oss}	Output Capacitance	V_{GS} =0V, V_{DS} =-10V, f=1MHz		80		pF
C _{rss}	Reverse Transfer Capacitance			70		pF
R_g	Gate resistance	V_{GS} =0V, V_{DS} =0V, f=1MHz		15	23	Ω
SWITCHI	NG PARAMETERS					
Q_g	Total Gate Charge			8.5	11	nC
Q_{gs}	Gate Source Charge	V_{GS} =-4.5V, V_{DS} =-10V, I_{D} =-3A		1.2		nC
Q_{gd}	Gate Drain Charge			2.1		nC
t _{D(on)}	Turn-On DelayTime			7.2		ns
t _r	Turn-On Rise Time	V_{GS} =-4.5V, V_{DS} =-10V, R_L =3.3 Ω ,		36		ns
$t_{D(off)}$	Turn-Off DelayTime	$R_{GEN}=6\Omega$		53		ns
t _f	Turn-Off Fall Time			56		ns
t _{rr}	Body Diode Reverse Recovery Time	I_F =-3A, dI/dt=100A/ μ s		37	49	ns
Q_{rr}	Body Diode Reverse Recovery Charge I _F =-3A, dI/dt=100A/μs			27		nC

A: The value of R $_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. copper, in a still air environment with T_A =25 $^\circ$ C. The value in any given application depends on the user's specific board design. The current rating is based on the t \leq 10s thermal resistance rating. B: Repetitive rating, pulse width limited by junction temperature.

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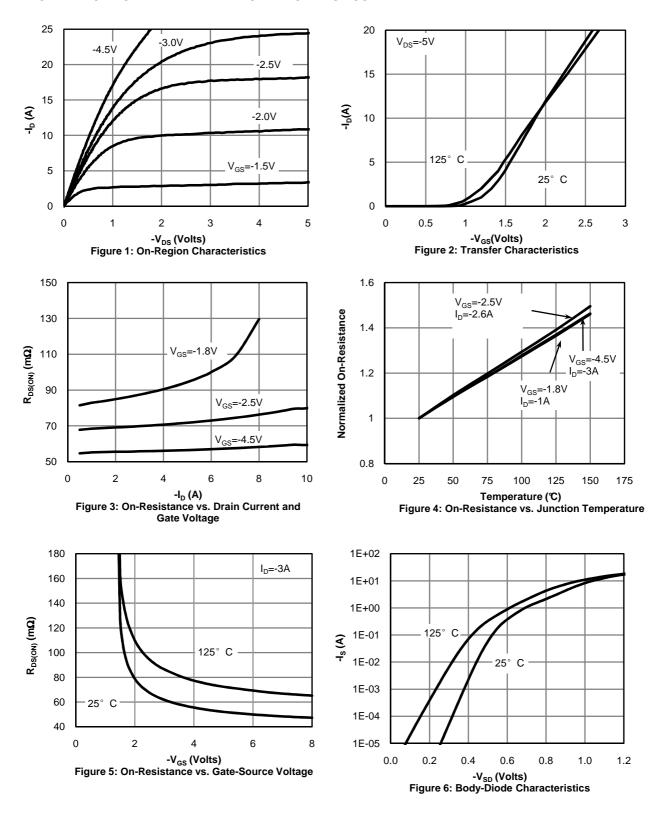
C. The R $_{\theta JA}$ is the sum of the thermal impedence from junction to lead R $_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using 300 μ s pulse width, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T $_{A}$ =25 $^{\circ}$ C. The SOA curve provides a single pulse rating.



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





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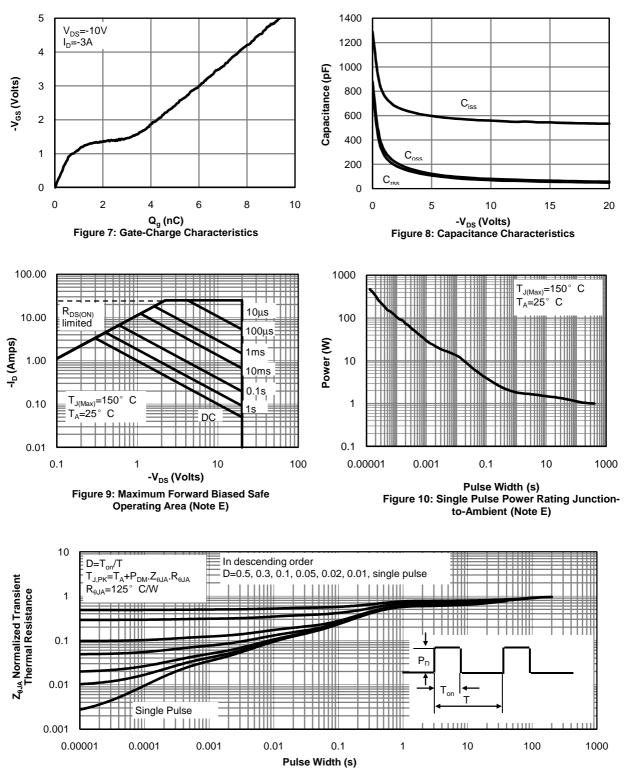
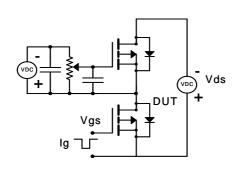
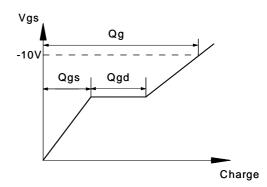


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)

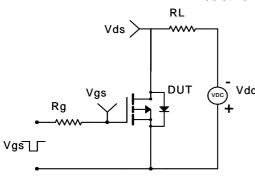


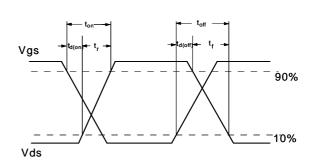
Gate Charge Test Circuit & Waveform





Resistive Switching Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms

